

FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. <b>03500.010106.6</b>		APPLICATION NO. <b>NOT YET ASSIGNED</b>	
				APPLICANT <b>TOSHIKAZU OHNISHI ET AL.</b>			
				FILING DATE <b>FILED HEREWITH</b>		GROUP <b>2879</b>	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		6,348,761 B1	2/02	Nomura et al.	313	495	6/94
		4,949,019	8/90	Isaka et al.	445	6	
		5,066,883	11/91	Yoshioka et al.	313	309	
		5,006,883	11/91	Yoshioka et al.	313	309	
		4,954,744	9/90	Suzuki et al.	313	336X	
		5,285,129	2/94	Takeda et al.	313	309X	
		5,256,936	10/93	Itoh et al.	313	309X	
		5,141,460	8/92	Jaskie et al.	313	309X	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
		0523702A1	1/93	EPO			Abstract
		1283749A	11/89	JAPAN			Abstract
		A1309242	12/89	JAPAN			No
		536731A1	4/93	EPO			
		1-309242	12/89	JAPAN			Translation
		0 299 461	1/89	EPO			
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		<b>"Metal Influence on Switching MIM Diodes", H. Pagnia, et al., Phys. Stat. Sol. (a), 111, 387 (1989)</b>		
		<b>"Scanning Tunnelling Microscopic Investigations of Electroformed Planar Metal-Insulator-Metal Diodes," H. Pagnia, N. Sotnik and W. Wirth, Int. J. Electronics, Vol. 69, No. 1, 25-32 (1990)</b>		
		<b>"Energy Distribution of Emitted Electrons from Electroformed MIM Structures: The Carbon Island Model," M. Bischoff, H. Pagnia and J. Trickl, Int. J. Electronics, Vol. 73, No. 5, 1009-1010 (1992)</b>		
		<b>"Thin Film Handbook," Committee 131 of Japanese Society for the Promotion of Art and Science</b>		
		<b>"On the Electron Emission from Evaporated Thin Au Films," M. Bischoff, R. Holzer and H. Pagnia, Physics Letters, Vol. 62A, No. 7 (October 3, 1977)</b>		
		<b>"The Electroforming Process in MIM Diodes," Vol. 85, R. Blessing, H. Pagnia and N. Sotnik, Thin Solid Films, 119-128 (1981)</b>		
		<b>"Evidence for the Contribution of an Adsorbate to the Voltage-Controlled Negative Resistance of Gold Island Film Diodes," R. Blessing, H. Pagnia and R. Schmitt, Thin Solid Films, Vol. 78, 397-401 (1981)</b>		
		<b>"Water-Influenced Switching in Discontinuous Au Film Diodes," R. Muller and H. Pagnia, Materials Letters, Vol. 2, No. 4A, 283-285 (March 1984)</b>		
		<b>"Influence of Organic Molecules on the Current-Voltage Characteristic of Planar MIM Diodes," H. Pagnia, N. Sotnik and H. Strauss, Phy. Stat. Sol., Vol. 90, 771-778 (1985)</b>		
		<b>"Influence of Gas Composition on Regeneration in Metal/Insulator/Metal Diodes," M. Borbonus, H. Pagnia and N. Sotnik, Thin Solid Films, Vol. 151, 333-342 (1987)</b>		
		<b>"Prospects for Metal/Non-Metal Microsystems: Sensors, Sources and Switches," H. Pagnia, Int. J. Electronics, Vol. 73, No. 5, 319-825 (1992)</b>		
		<b>W.P. Dyke, et al., "Field Emission," Advances in Electronics and Electron Physics, 1956, pp. 90-185</b>		
		<b>C.A. Spindt, et al. "Physical Properties of Thin-Film Field Emission Cathodes With Molybdenum Cones," J. Appl. Phys., Vol. 47 (1976) pp. 5248-5263</b>		
		<b>C.A. Mead, "Operation of Tunnel-Emission Devices," J. Appl. Phys., Vol. 32, (1961) pp. 646-652</b>		
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		G. Dittmer, "Electrical Conduction and Electron Emission of Discontinuous Thin Films," Thin Solid Films, 9, (1972) pp. 317-328	
		H. Hartwell, et al, "Strong Electron Emission From Patterned Tin-Indium Oxide Thin Films," Int'l Electron Devices Meeting (1975) pp. 519-521	
		M. Araki, "Electroforming and Electron Emission of Carbon Thin Films," J. Vac. Soc. Japan, 26, (1983) pp. 22-29	
		"Carbon-Nanoslit Model for the Electroforming Process in MIM Structures," M. Bischoff, Int. J. Electronics, Vol. 70, No. 3, 491-498 (1991)	
		Patent Abstracts of Japan, vol. 14, no. 1 08 (E-896) (4051), Feb 27, 1990	
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				APPLICANT <b>Toshikazu Ohnishi t al.</b>			
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		6,171,162 B1	01/09/01	Iwasaki et al.	445	6	
		6,169,356 B1	01/02/01	Ohnishi et al.	313	495	
		6,184,610 B1	02/06/01	Shibata et al.	313	309	
		6,246,168 B1	06/12/01	Kishi et al.	313	495	
		6,384,541 B1	05/07/02	Ohnishi et al.	315	169.3	
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
		1069826 A	3/10/93	China	H01J	1/30	Abst. & Trans.
		1069828 A	3/10/93	China	H01J	19/42	Abst., Trans. & EP 0 513 777
		1-031332	02/01/89	Japan	H01J	29/48	Abst.
		0 513 777 A2	11/19/92	EPO	H01J	1/30	English
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